

Search Notes

Application/Control No.

10/030,070

Examiner

Annan Q. Shang

Applicant(s)/Patent under
Reexamination

LETELLIER, PHILIPPE

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
725	34-36,39-43,97,109,110-113	2/27/2006	A.S.
709	203-207	2/27/2006	A.S.
709	230-231	2/27/2006	A.S.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR